Searcl	n Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/767,039	FURUKAWA ET AL.
Examiner	Art Unit
Phat X. Cao	2814

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
EAST: IS&R (updated searches)	2/2/2006	PC